## Issue Classification



10823529

Lam, David

Examiner

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JIN ET AL.

Applicant(s)/Patent Under Reexamination

Art Unit

2827

ORIGINAL							INTERNATIONAL CLASSIFICATION								
CLASS SI				SUBCLASS		CLAIMED						NON-CLAIMED			
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NONE		DAVID I 444				1	17	Total Claims Allowed:							

DAVID LAM
PRIMARY EXAMINER

(Date)

Lam, David

(Primary Examiner)

(Assistant Examiner)

Examiner)

(Date)

O.G. Print Figure 6K

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O.G. Print Claim(s)